74F00 Quad 2-Input NAND Gate

FAIRCHILD

SEMICONDUCTOR

74F00 Quad 2-Input NAND Gate

General Description

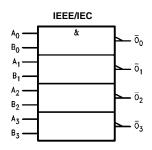
This device contains four independent gates, each of which performs the logic NAND function.

Ordering Code:

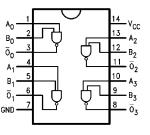
Order Number	Package Number	Package Description					
74F00SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow					
74F00SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide					
74F00PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide					

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
A _n , B _n	Inputs	1.0/1.0	20 µA/–0.6 mA	
Ōn	Outputs	50/33.3	–1 mA/20 mA	

December Revised Se

74F00

Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C			
Ambient Temperature under Bias	-55°C to +125°C			
Junction Temperature under Bias	$-55^{\circ}C$ to $+150^{\circ}C$			
V _{CC} Pin Potential to Ground Pin	-0.5V to +7.0V			
Input Voltage (Note 2)	-0.5V to +7.0V			
Input Current (Note 2)	-30 mA to +5.0 mA			
Voltage Applied to Output				
in HIGH State (with $V_{CC} = 0V$)				
Standard Output	–0.5V to V _{CC}			
3-STATE Output	-0.5V to +5.5V			
Current Applied to Output				
in LOW State (Max)	twice the rated I _{OL} (mA)			
ESD Last Passing Voltage (Min)	4000V			

Recommended Operating Conditions

Free Air Ambient Temperature
Supply Voltage

 $0^{\circ}C$ to $+70^{\circ}C$ +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

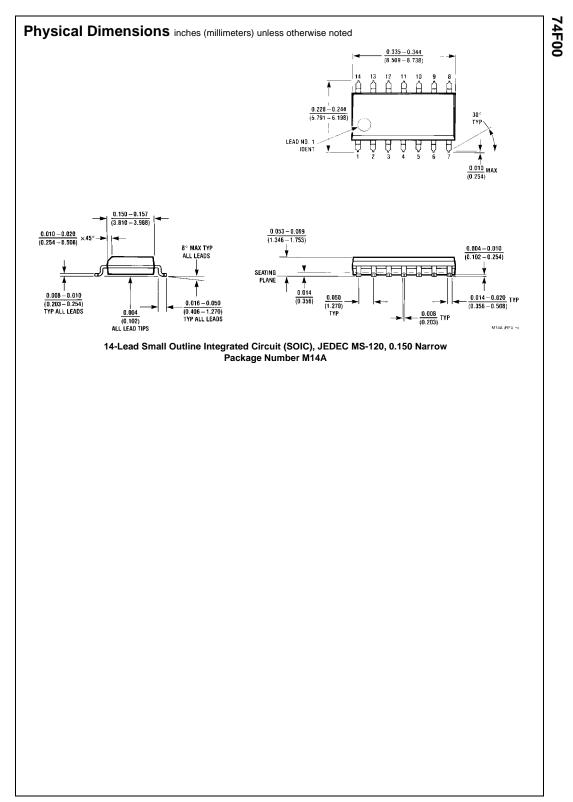
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

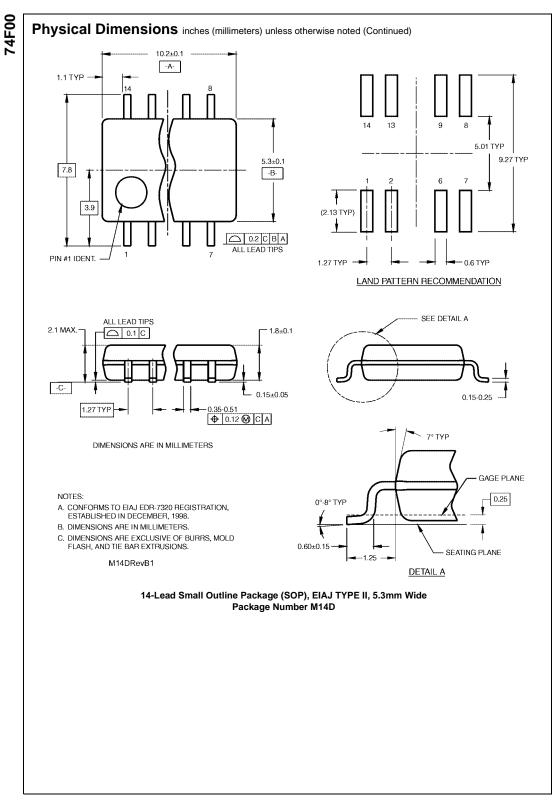
DC Electrical Characteristics

Symbol	ol Parameter		Min	Тур	Max	Units	V _{cc}	Conditions		
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signa		
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal		
V _{CD}	Input Clamp Diode Voltag	je			-1.2	V	Min	I _{IN} = -18 mA		
V _{OH}	Output HIGH 10% V _{CC}		2.5			V	Min	I _{OH} = -1 mA		
	Voltage	5% V _{CC}	2.7					$I_{OH} = -1 \text{ mA}$		
V _{OL}	Output LOW Voltage	10% V _{CC}			0.5	V	Min	I _{OL} = 20 mA		
IIH	Input HIGH				5.0	μA	Max	V _{IN} = 2.7V		
I _{BVI}	Current Input HIGH Current				7.0	μA	Max	V _{IN} = 7.0V		
	Breakdown Test									
ICEX	Output HIGH				50	μA	Max	$V_{OUT} = V_{CC}$		
	Leakage Current									
V _{ID}	Input Leakage		4.75			V	0.0	I _{ID} = 1.9 μA		
	Test							All other pins grounded		
I _{OD}	Output Leakage				3.75	μΑ	0.0	$V_{IOD} = 150 \text{ mV}$		
	Circuit Current							All other pins grounded		
IIL	Input LOW Current				-0.6	mA	Max	$V_{IN} = 0.5V$		
I _{OS}	Output Short-Circuit Curr	ent	-60		-150	mA	Max	V _{OUT} = 0V		
I _{CCH}	Power Supply Current			1.9	2.8	mA	Max	V _O = HIGH		
I _{CCL}	Power Supply Current			6.8	10.2	mA	Max	$V_{O} = LOW$		

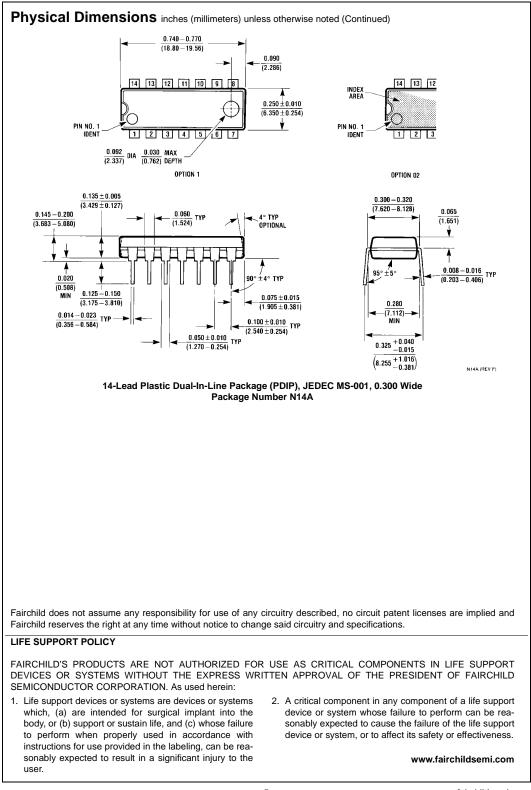
AC Electrical Characteristics

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$\label{eq:T_A} \begin{split} T_A = -55^\circ C \ to \ +125^\circ C \\ V_{CC} = +5.0V \\ C_L = 50 \ pF \end{split}$		$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	Min	Max	
t _{PLH}	Propagation Delay	2.4	3.7	5.0	2.0	7.0	2.4	6.0	ns
t _{PHL}	$A_n, B_n \text{ to } \overline{O}_n$	1.5	3.2	4.3	1.5	6.5	1.5	5.3	115





www.fairchildsemi.com



74F00 Quad 2-Input NAND Gate

www.fairchildsemi.com